TOSHIBA Photocoupler IRED & Photo IC

TLP558

Isolated Bus Driver
High Speed Line Receiver
Microprocessor System Interfaces
MOS FET Gate Driver
Transistor Inverter

The TOSHIBA TLP558 consists of an infrared emitting diode and integrated high gain, high speed photodetector.

This unit is 8-lead DIP package.

The detector has a three state output stage that provides source drive and sink drive, and built-in schmitt trigger. The detector IC has an internal shield that provides a guaranteed common mode transient immunity of 1000V / µs. TLP558 is inverter logic type. For buffer logic type, TLP555 is in line-up.

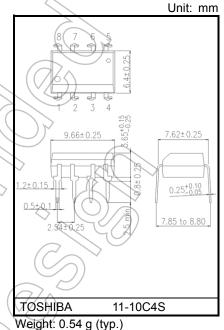
- Input current: IF=1.6 mA (max)
- Power supply voltage: VCC=4.5 to 20 V
- Switching speed: tpHL, tpLH=400ns (max)
- Common mode transient immunity: ±1000V/µs (min)/
- Guaranteed performance over temperature: -25 to 85°C
- Isolation voltage: 2500Vrms (min)
- UL-recognized: UL 1577, File No.E67349
- cUL-recognized: CSA Component Acceptance Service

No.5A File No.E67349

Truth Table

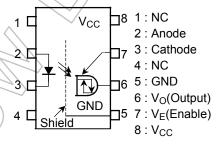
Input	Enable	Output
Н	H	
L	Н	Н
Н	Ĺ	Z
L	⟨\Q	Z

A $0.1\mu F$ bypass capacitor must be connected between pins 8 and 5.

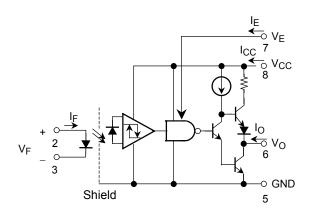


Weight. 0.54 g (typ.)

Pin Configuration (top view)



Schematic



Start of commercial production 1987-05

Absolute Maximum Ratings

	Charactersitic		Symbol	Rating	Unit
	Forward current		lF	10	mA
	Peak transient forward current	(Note 1)	IFPT	1	Α
쁘	Reverse voltage		VR	5	V
	Diode power dissipation		P_{D}	45	mW
	Output current		lo	40 / -25	mA
	Peak output current	(Note 2)	lop	80 / -50	mA
	Output voltage		⟨Vo (-0.5 to 20	V
or	Supply voltage		Vcc	-0.5 to 20	V
Detector	Three state enabel voltage		VE	-0.5 to 20	V
۵	Output power dissipation		Po	100	mW
	Output power dissipation derating (Ta > 70 °C)	<	ΔΡΟ/ΔΤα	-1.8	mW/°C
	Total package power dissipation	6	Рт	200	mW
	Total package power dissipation derating (Ta > 70 °C)		ΔΡΤ/ΔΤα	-3.6	mW/°C
Оре	erating temperature range		T _{opr}	-40 to 85	/,c
Sto	Storage temperature range			-55 to 125	°C
Lea	d solder temperature(10 s)	(Note 3)	T _{sol}	260	°C
Isol	ation voltage (AC, 60 s, R.H. ≤ 60 %, Ta=25°C)	BVs	2500	Vrms	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- Note 1: Pulse width \leq 1 µs, 300 pps.
- Note 2: Pulse width $\leq 5\mu$ s, duty ratio ≤ 0.025 .
- Note 3: 1.6 mm below seating plane.
- Note 4: Device considered a two terminal device: Pins 1, 2, 3 and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.

Recommended Operating Conditions

Characteristic	Symbol	Min	Тур.	Max	Unit
Input current, on	I _{F(ON)}	2 (Note 1)	_	5	mA
Input voltage, off	VF(OFF)	0	_	0.8	V
Supply voltage	Vcc	4.5	_	20	V
Enable voltage high	VEH	2.0	_	20	V
Enable voltage low	V _{EL}	0	_	0.8	V
Fan out(TTL load)	N	_	_	4	_
Operating temperature	T _{opr}	-25	_	85	°C

Note: Recommended operating conditions are given as a design guideline to obtain expected performance of the device. Additionally, each item is an independent guideline respectively. In developing designs using this product, please confirm specified characteristics shown in this document.

Note 1: 2 mA condition permits at least 20 % CTR degradation guardband. Initial switching threshold is 1.6 mA or less.



Electrical Characteristics (unless otherwise specified, Ta = -25 to 85°C, Vcc = 4.5 to 20V)

Characteristic	Symbol	Test (Min	Тур.	Max	Unit	
Input forward voltage	V _F	I _F = 5 mA, Ta =	_	1.55	1.7	V	
Temperature coefficient of forward voltage	ΔV _F / ΔTa	IF = 5 mA	_	-2.0	_	mV / °C	
Input reverse current	I _R	V _R = 5 V, Ta = 2	5 °C	-	_	10	μΑ
Input capacitance	Ст	V _F = 0 V, f = 1 M	1Hz, Ta = 25 °C	+(45	ı	pF
Output leakage current	Іонн	V	V _O = V _E = 5.5 V			100	μA
(Vo > Vcc)	IONN	V _{CC} = 4.5 V	V _O = V _E = 20 V	(//-5)	0.01	500	μΛ
Logic low output voltage	VoL	I _{OL} = 6.4 mA, I _F V _E = 2 V	= 1.6 mA		0.4	0.5	٧
Logic high output voltage	Voн	I _{OH} = -2.6 mA, V _E = 2 V	/F = 0.8 V	2.4	3.3	_	V
Logic low enable current	lEL	VE = 0.4 V	4/ >	_	-0.13	-0.32	mA
		VE = 2.7 V	V _E = 2.7 V			> 20	
Logic high enable current	IEH	V _E = 5.5 V		♦- ($\mathcal{O}_{\mathcal{I}_{\mathcal{I}_{\mathcal{I}}}}$	100	μΑ
		V _E = 20 V			0.01	250	
Logic low enable voltage	VEL			(4	<u> </u>	0.8	V
Logic high enable voltage	VEH		$\stackrel{\searrow}{}$	2.0	/ —	_	V
Logic low supply current	Iccl	IF = 5 mA	$V_{CC} = V_E = 5.5 V$	74	4.0	6.0	mA
			Vcc = VE = 20 V	J}	4.6	7.5	
Logic high supply current	Іссн	VF = 0.V	$V_{CC} = V_E = 5.5 \text{ V}$	_	4.2	6.0	mA
		7. 4.	V _{CC} = V _E = 20 V	_	4.7	7.5	
	IOZL	V _E = 0 V V _E = 0.8 V	V _O = 0.4 V	_	_	-20	
High impedance state output current	lozh	I _F = 5 mA V _E = 0.8 V	Vo = 2.4 V	_	_	20	μΑ
			V _O = 5.5 V	_	_	100	
			V _O = 20 V	_	1	500	
Logic low short circuit	Jost	NF = 5 mA	V _O = V _{CC} = 5.5 V	25	55	_	mA
output current (Note 1)	1032	VE = 2 V	V _O = V _{CC} = 20 V	40	80	_	110.
Logic high short circuit	Iosh	VF = 0 V, VO = 0	OND VCC = 5.5 V	-10	-25	_	- mA
output current (Note 1)	IOSH	V _E = 2 V	V _{CC} = 20 V	-25	-60	_	
Input current logic low output	IFD	V _E = 2 V, I _O = 6. V _O < 0.4 V	_	0.4	1.6	mA	
Input voltage logic high output	VFH	VE = 2 V, I _O = -2.6 mA V _O > 2.4 V		0.8	_	_	V
Input current hysteresis	IHYS	V _C C = V _E = 5 V	_	0.05	ı	mA	
Resistance (input-output)	Rs	V _S = 500 V, R.H Ta = 25 °C	5×10 ¹⁰	10 ¹⁴	_	Ω	
Capacitance(input-output)	Cs	V _S = 0 V, f = 1 N	1Hz, Ta = 25 °C (Note 2)	_	1.0	_	pF

Note: All typical values are at Ta = 25 °C, VCC = 5 V, IF(ON) = 3 mA unless otherwise specified.

Note 2: Device considered a two terminal device: Pins 1, 2, 3 and 4 shorted together, and pins 5, 6, 7 and 8 shorted together.

Note 1: Duration of output short circuit time should not exceed 10 ms.

Switching Characteristics (unless otherwise specified, Vcc = 4.5 to 20V, Ta = 25°C)

Characteristic		Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation delay time to logic high output	(Note 1)	t _{pLH}		I _F = 3→ 0 mA	_	250	400	ns
Propagation delay time to logic low output	(Note 1)	t _{pHL}	1	I _F = 0→ 3 mA		270	400	ns
Output rise time (10-90%)		tr		I _F = 3→ 0 mA, V _{CC} = 5 V	+	35	75	ns
Output fall time (90-10%)		t _f		I _F = 0→ 3 mA, V _{CC} = 5 V		20	75	ns
Common mode transient immunity at logic high output	(Note 2)	Смн		I _F = 0 mA, V _{CM} = 50 V V _O (Min) = 2 V	1000	_	-	V / µs
Common mode transient immunity at logic low output	(Note 2)	Смь	3	I _F = 1.6 mA, V _{CM} = 50 V V _{O (Max)} = 0.8 V	-1000	_	-	V / µs

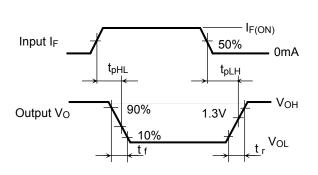
Note: All typical values are at Ta = 25 °C, Vcc = 5 V

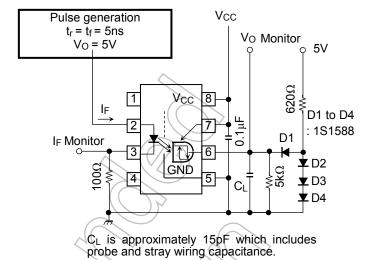
- Note: A ceramic capacitor (0.1 µF) should be connected from pin 8 to pin 5 to stabilize the operation of the high gain linear amplifier. Failure to provide the bypassing may impair the switching property. The total lead length between capacitor and coupler should not exceed 1cm.
- Note 1: The tpLH propagation delay is measured from the 50 % point on the trailing edge of the input pulse to the 1.3 V point on the leading edge of the output pulse. The tpHL propagation delay is measured from the 50 % point on the leading edge of the input pulse to the 1.3 V point on the trailing edge of the output pulse.
- Note 2: CML is the maximum rate of fall of the common mode voltage that can be sustained with the output voltage in the logic low state (VO < 0.8 V).

CMH is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic state (VO > 2.0 V).

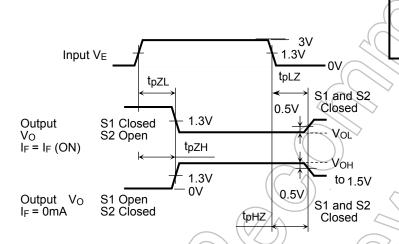


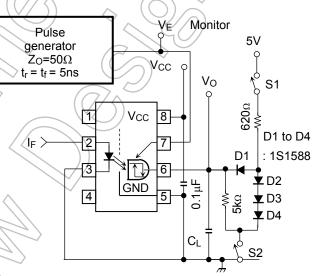
Test Circuit 1: tplh, tphl, tr and tf





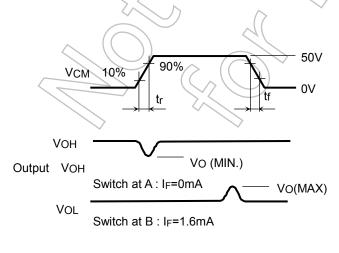
Test Circuit 2: tpHz, tpZH, tpLz and tpZL



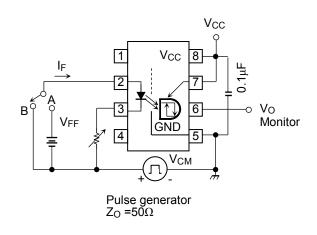


C_L is approximately 15_pF which includes probe and stray wiring capacitance.

Test Circuit 3: Common Mode Transient Immunity



$$CMH = \frac{45(V)}{tf(\mu s)}, CML = \frac{45(V)}{tf(\mu s)}$$



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